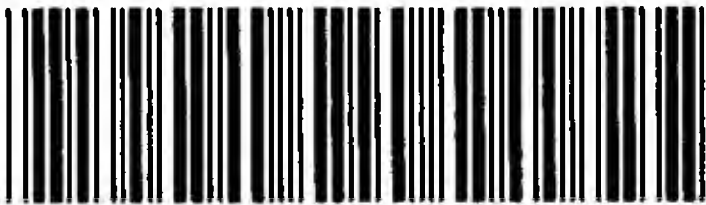


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,097	WENG, YIH-SHIN	
	Examiner	Art Unit	
	Parul Gupta	2627	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PG Pub clm search, see interference search printout			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated EAST search (see search history printout).	6/21/2007	PG